

## Ultra Low ON-Resistance, +1.65V to +4.5V, Single Supply, Dual SPDT Analog Switch

The Intersil ISL54050 device is a low ON-resistance, low voltage, bidirectional, dual single-pole/double-throw (SPDT) analog switch designed to operate from a single +1.65V to +4.5V supply. Targeted applications include battery powered equipment that benefit from low  $r_{ON}$  (0.29 $\Omega$ ) and fast switching speeds ( $t_{ON}$  = 40ns,  $t_{OFF}$  = 20ns). The digital logic input is 1.8V logic-compatible when using a single +3V supply.

Cell phones, for example, often face ASIC functionality limitations. The number of analog input or GPIO pins may be limited and digital geometries are not well suited to analog switch performance. This part may be used to “mux-in” additional functionality while reducing ASIC design risk. The ISL54050 is offered in small form factor package, alleviating board space limitations.

The ISL54050 is a committed dual single-pole/double-throw (SPDT) that consists of two normally open (NO) and two normally closed (NC) switches. This configuration can be used as a dual 2-to-1 multiplexer. The ISL54050 is pin compatible with the NLAS5223 and NLAS5223L.

**TABLE 1. FEATURES AT A GLANCE**

	<b>ISL54050</b>
<b>Number of Switches</b>	2
<b>SW</b>	SPDT or 2-1 MUX
<b>4.3V <math>r_{ON}</math></b>	0.29 $\Omega$
<b>4.3V <math>t_{ON}/t_{OFF}</math></b>	40ns/20ns
<b>3V <math>r_{ON}</math></b>	0.33 $\Omega$
<b>3V <math>t_{ON}/t_{OFF}</math></b>	50ns/27ns
<b>1.8V <math>r_{ON}</math></b>	0.55 $\Omega$
<b>1.8V <math>t_{ON}/t_{OFF}</math></b>	70ns/54ns
<b>Package</b>	10 Ld 1.8mmx1.4mmx0.5mm $\mu$ TQFN

## Ordering Information

<b>PART NUMBER (Note)</b>	<b>PART MARKING</b>	<b>TEMP. RANGE (°C)</b>	<b>PACKAGE (Pb-free)</b>	<b>PKG. DWG. #</b>
ISL54050IRUZ-T*	A	-40 to +85	10 Ld 1.8mmx1.4mmx0.5mm $\mu$ TQFN Tape and Reel	L10.1.8x1.4A

\*Please refer to TB347 for details on reel specifications.

NOTE: These Intersil Pb-free plastic packaged products employ special Pb-free material sets; molding compounds/die attach materials and NiPdAu plate - e4 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations. Intersil Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J STD-020.

## Features

- Pin Compatible Replacement for the NLAS5223 and NLAS5223L
- ON-Resistance ( $r_{ON}$ )
  - $V_+ = +4.3V$  . . . . . 0.29 $\Omega$
  - $V_+ = +3.0V$  . . . . . 0.33 $\Omega$
  - $V_+ = +1.8V$  . . . . . 0.55 $\Omega$
- $r_{ON}$  Matching Between Channels . . . . . 0.06 $\Omega$
- $r_{ON}$  Flatness Across Signal Range . . . . . 0.03 $\Omega$
- Single Supply Operation. . . . . +1.65V to +4.5V
- Low Power Consumption ( $P_D$ ) . . . . . <0.45 $\mu$ W
- Fast Switching Action ( $V_+ = +4.3V$ )
  - $t_{ON}$  . . . . . 40ns
  - $t_{OFF}$  . . . . . 20ns
- ESD HBM Rating . . . . . >8kV
- Break-before-Make
- 1.8V Logic Compatible (+3V supply)
- Low ICC Current when VinH is not at the V+ Rail
- Available in 10 Ld 1.8mmx1.4mmx0.5mm  $\mu$ TQFN
- Pb-Free (RoHS Compliant)

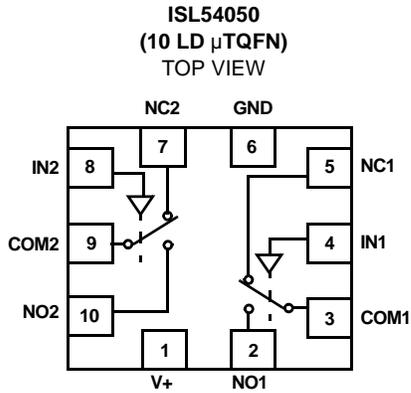
## Applications

- Battery powered, Handheld, and Portable Equipment
  - Cellular/mobile Phones
  - Pagers
  - Laptops, Notebooks, Palmtops
- Portable Test and Measurement
- Medical Equipment
- Audio and Video Switching

## Related Literature

- Technical Brief TB363 “Guidelines for Handling and Processing Moisture Sensitive Surface Mount Devices (SMDs)”
- Application Note AN557 “Recommended Test Procedures for Analog Switches”

**Pinout** (Note 1)



NOTE:

1. Switches Shown for Logic "0" Input.

**Truth Table**

LOGIC	NC1 and NC2	NO1 and NO2
0	ON	OFF
1	OFF	ON

NOTE: Logic "0"  $\leq 0.5V$ . Logic "1"  $\geq 1.4V$  with a 3V supply.

**Pin Descriptions**

PIN	FUNCTION
V+	System Power Supply Input (+1.65V to +4.5V)
GND	Ground Connection
IN	Digital Control Input
COM	Analog Switch Common Pin
NO	Analog Switch Normally Open Pin
NC	Analog Switch Normally Closed Pin

**Absolute Maximum Ratings**

V+ to GND	-0.5V to 5.5V
Input Voltages	
NO, NC, IN (Note 2)	-0.5V to ((V+) + 0.5V)
Output Voltages	
COMx (Note 2)	-0.5V to ((V+) + 0.5V)
Continuous Current NO, NC, or COM	±300mA
Peak Current NO, NC, or COM (Pulsed 1ms, 10% Duty Cycle, Max)	±500mA
ESD Rating	
Human Body Model	>8kV
Machine Model	>500V
Charged Device Model	>1.4kV

**Thermal Information**

Thermal Resistance (Typical)	$\theta_{JA}$ (°C/W)
10 Ld $\mu$ TQFN Package (Note 3)	143
Maximum Junction Temperature (Plastic Package)	+150°C
Maximum Storage Temperature Range	-65°C to +150°C
Pb-Free Reflow Profile	see link below
<a href="http://www.intersil.com/pbfree/Pb-FreeReflow.asp">http://www.intersil.com/pbfree/Pb-FreeReflow.asp</a>	

**Operating Conditions**

Temperature Range	-40°C to +85°C
-------------------	----------------

CAUTION: Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions may adversely impact product reliability and result in failures not covered by warranty.

NOTES:

2. Signals on NC, NO, IN, or COM exceeding V+ or GND are clamped by internal diodes. Limit forward diode current to maximum current ratings.
3.  $\theta_{JA}$  is measured with the component mounted on a high effective thermal conductivity test board in free air. See Tech Brief TB379 for details.

**Electrical Specifications - 4.3V Supply**

Test Conditions: V+ = +3.9V to +4.5V, GND = 0V, V<sub>INH</sub> = 1.6V, V<sub>INL</sub> = 0.5V (Note 4), Unless Otherwise Specified.

PARAMETER	TEST CONDITIONS	TEMP (°C)	MIN (Notes 5, 8)	TYP	MAX (Notes 5, 8)	UNITS
<b>ANALOG SWITCH CHARACTERISTICS</b>						
Analog Signal Range, V <sub>ANALOG</sub>		Full	0		V+	V
ON-Resistance, r <sub>ON</sub>	V+ = 3.9V, I <sub>COM</sub> = 100mA, V <sub>NO</sub> or V <sub>NC</sub> = 0V to V+ (see Figures 5, 9)	25		0.30	0.5	$\Omega$
		Full		0.35	0.7	$\Omega$
r <sub>ON</sub> Matching Between Channels, $\Delta r_{ON}$	V+ = 3.9V, I <sub>COM</sub> = 100mA, V <sub>NO</sub> or V <sub>NC</sub> = Voltage at max r <sub>ON</sub> (Notes 7, 9)	25		0.06	0.07	$\Omega$
		Full		0.08	0.08	$\Omega$
r <sub>ON</sub> Flatness, r <sub>FLAT(ON)</sub>	V+ = 3.9V, I <sub>COM</sub> = 100mA, V <sub>NO</sub> or V <sub>NC</sub> = 0V to V+ (Notes 6, 9)	25		0.03	0.15	$\Omega$
		Full		0.04	0.15	$\Omega$
NO or NC OFF Leakage Current, I <sub>NO(OFF)</sub> or I <sub>NC(OFF)</sub>	V+ = 4.5V, V <sub>COM</sub> = 0.3V, 3V, V <sub>NO</sub> or V <sub>NC</sub> = 3V, 0.3V	25	-100		100	nA
		Full	-195		195	nA
COM ON Leakage Current, I <sub>COM(ON)</sub>	V+ = 4.5V, V <sub>COM</sub> = 0.3V, 3V, or V <sub>NO</sub> or V <sub>NC</sub> = 0.3V, 3V or floating	25	-100		100	nA
		Full	-195		195	nA
<b>DYNAMIC CHARACTERISTICS</b>						
Turn-ON Time, t <sub>ON</sub>	V+ = 3.9V, V <sub>NO</sub> or V <sub>NC</sub> = 3.0V, R <sub>L</sub> = 50 $\Omega$ , C <sub>L</sub> = 35pF (see Figure 1)	25		40		ns
		Full		50		ns
Turn-OFF Time, t <sub>OFF</sub>	V+ = 3.9V, V <sub>NO</sub> or V <sub>NC</sub> = 3.0V, R <sub>L</sub> = 50 $\Omega$ , C <sub>L</sub> = 35pF (see Figure 1)	25		20		ns
		Full		30		ns
Break-Before-Make Time Delay, t <sub>D</sub>	V+ = 4.5V, V <sub>NO</sub> or V <sub>NC</sub> = 3.0V, R <sub>L</sub> = 50 $\Omega$ , C <sub>L</sub> = 35pF (see Figure 3)	Full		8		ns
Charge Injection, Q	C <sub>L</sub> = 1.0nF, V <sub>G</sub> = 0V, R <sub>G</sub> = 0 $\Omega$ (see Figure 2)	25		170		pC
OFF-Isolation	R <sub>L</sub> = 50 $\Omega$ , C <sub>L</sub> = 5pF, f = 100kHz, V <sub>COM</sub> = 1V <sub>RMS</sub> (see Figure 4)	25		62		dB
Crosstalk (Channel-to-Channel)	R <sub>L</sub> = 50 $\Omega$ , C <sub>L</sub> = 5pF, f = 100kHz, V <sub>COM</sub> = 1V <sub>RMS</sub> (see Figure 6)	25		-85		dB
Total Harmonic Distortion	f = 20Hz to 20kHz, V <sub>COM</sub> = 2V <sub>P-P</sub> , R <sub>L</sub> = 600 $\Omega$	25		0.005		%
NO or NC OFF Capacitance, C <sub>OFF</sub>	f = 1MHz, V <sub>NO</sub> or V <sub>NC</sub> = V <sub>COM</sub> = 0V (see Figure 7)	25		62		pF

# ISL54050

## Electrical Specifications - 4.3V Supply

Test Conditions:  $V_+ = +3.9V$  to  $+4.5V$ ,  $GND = 0V$ ,  $V_{INH} = 1.6V$ ,  $V_{INL} = 0.5V$  (Note 4), Unless Otherwise Specified. **(Continued)**

PARAMETER	TEST CONDITIONS	TEMP (°C)	MIN (Notes 5, 8)	TYP	MAX (Notes 5, 8)	UNITS
COM ON Capacitance, $C_{COM(ON)}$	$f = 1MHz$ , $V_{NO}$ or $V_{NC} = V_{COM} = 0V$ (see Figure 7)	25		176		pF
<b>POWER SUPPLY CHARACTERISTICS</b>						
Power Supply Range		Full	1.65		4.5	V
Positive Supply Current, $I_+$	$V_+ = +4.5V$ , $V_{IN} = 0V$ or $V_+$	25			0.1	$\mu A$
		Full			1	$\mu A$
Positive Supply Current, $I_+$	$V_+ = +4.2V$ , $V_{IN} = 2.85V$	25			12	$\mu A$
<b>DIGITAL INPUT CHARACTERISTICS</b>						
Input Voltage Low, $V_{INL}$		Full			0.5	V
Input Voltage High, $V_{INH}$		Full	1.6			V
Input Current, $I_{INH}$ , $I_{INL}$	$V_+ = 4.5V$ , $V_{IN} = 0V$ or $V_+$ (Note 9)	Full	-0.5		0.5	$\mu A$

## Electrical Specifications - 3V Supply

Test Conditions:  $V_+ = +2.7V$  to  $+3.3V$ ,  $GND = 0V$ ,  $V_{INH} = 1.4V$ ,  $V_{INL} = 0.5V$  (Note 4), Unless Otherwise Specified.

PARAMETER	TEST CONDITIONS	TEMP (°C)	MIN (Notes 5, 8)	TYP	MAX (Notes 5, 8)	UNITS
<b>ANALOG SWITCH CHARACTERISTICS</b>						
Analog Signal Range, $V_{ANALOG}$		Full	0		$V_+$	V
ON-Resistance, $r_{ON}$	$V_+ = 2.7V$ , $I_{COM} = 100mA$ , $V_{NO}$ or $V_{NC} = 0V$ to $V_+$ (see Figure 5)	25		0.35	0.5	$\Omega$
		Full			0.7	$\Omega$
$r_{ON}$ Matching Between Channels, $\Delta r_{ON}$	$V_+ = 2.7V$ , $I_{COM} = 100mA$ , $V_{NO}$ or $V_{NC} =$ Voltage at max $r_{ON}$ (Note 7)	25		0.06	0.07	$\Omega$
		Full			0.08	$\Omega$
$r_{ON}$ Flatness, $r_{FLAT(ON)}$	$V_+ = 2.7V$ , $I_{COM} = 100mA$ , $V_{NO}$ or $V_{NC} = 0V$ to $V_+$ (Note 6)	25		0.03	0.15	$\Omega$
		Full			0.15	$\Omega$
NO or NC OFF Leakage Current, $I_{NO(OFF)}$ or $I_{NC(OFF)}$	$V_+ = 3.3V$ , $V_{COM} = 0.3V, 3V$ , $V_{NO}$ or $V_{NC} = 3V, 0.3V$	25		0.9		nA
		Full		30		nA
COM ON Leakage Current, $I_{COM(ON)}$	$V_+ = 3.3V$ , $V_{COM} = 0.3V, 3V$ , or $V_{NO}$ or $V_{NC} = 0.3V, 3V$ , or floating	25		0.8		nA
		Full		30		nA
<b>DYNAMIC CHARACTERISTICS</b>						
Turn-ON Time, $t_{ON}$	$V_+ = 2.7V$ , $V_{NO}$ or $V_{NC} = 1.5V$ , $R_L = 50\Omega$ , $C_L = 35pF$ (see Figure 1)	25		50		ns
		Full		60		ns
Turn-OFF Time, $t_{OFF}$	$V_+ = 2.7V$ , $V_{NO}$ or $V_{NC} = 1.5V$ , $R_L = 50\Omega$ , $C_L = 35pF$ (see Figure 1)	25		27		ns
		Full		35		ns
Break-Before-Make Time Delay, $t_D$	$V_+ = 3.3V$ , $V_{NO}$ or $V_{NC} = 1.5V$ , $R_L = 50\Omega$ , $C_L = 35pF$ (see Figure 3)	Full		9		ns
Charge Injection, Q	$C_L = 1.0nF$ , $V_G = 0V$ , $R_G = 0\Omega$ (see Figure 2)	25		94		pC
OFF-Isolation	$R_L = 50\Omega$ , $C_L = 5pF$ , $f = 100kHz$ , $V_{COM} = 1V_{RMS}$ (see Figure 4)	25		62		dB
Crosstalk (Channel-to-Channel)	$R_L = 50\Omega$ , $C_L = 5pF$ , $f = 100kHz$ , $V_{COM} = 1V_{RMS}$ (see Figure 6)	25		-85		dB
Total Harmonic Distortion	$f = 20Hz$ to $20kHz$ , $V_{COM} = 2V_{P-P}$ , $R_L = 600\Omega$	25		0.005		%
NO or NC OFF Capacitance, $C_{OFF}$	$f = 1MHz$ , $V_{NO}$ or $V_{NC} = V_{COM} = 0V$ (see Figure 7)	25		65		pF
COM ON Capacitance, $C_{COM(ON)}$	$f = 1MHz$ , $V_{NO}$ or $V_{NC} = V_{COM} = 0V$ (see Figure 7)	25		181		pF

**Electrical Specifications - 3V Supply**

Test Conditions:  $V_+ = +2.7V$  to  $+3.3V$ ,  $GND = 0V$ ,  $V_{INH} = 1.4V$ ,  $V_{INL} = 0.5V$  (Note 4), Unless Otherwise Specified. **(Continued)**

PARAMETER	TEST CONDITIONS	TEMP (°C)	MIN (Notes 5, 8)	TYP	MAX (Notes 5, 8)	UNITS
<b>POWER SUPPLY CHARACTERISTICS</b>						
Positive Supply Current, $I_+$	$V_+ = +3.6V$ , $V_{IN} = 0V$ or $V_+$	25		0.01		$\mu A$
		Full		0.52		$\mu A$
<b>DIGITAL INPUT CHARACTERISTICS</b>						
Input Voltage Low, $V_{INL}$		25			0.5	V
Input Voltage High, $V_{INH}$		25	1.4			V
Input Current, $I_{INH}$ , $I_{INL}$	$V_+ = 3.3V$ , $V_{IN} = 0V$ or $V_+$ (Note 9)	Full	-0.5		0.5	$\mu A$

**Electrical Specifications - 1.8V Supply**

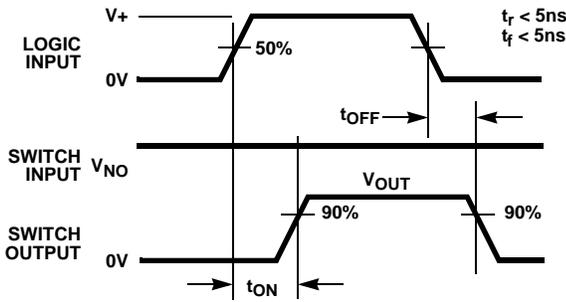
Test Conditions:  $V_+ = +1.65V$  to  $+2V$ ,  $GND = 0V$ ,  $V_{INH} = 1.0V$ ,  $V_{INL} = 0.4V$  (Note 4), Unless Otherwise Specified.

PARAMETER	TEST CONDITIONS	TEMP (°C)	MIN (Notes 5, 8)	TYP	MAX (Notes 5, 8)	UNITS
<b>ANALOG SWITCH CHARACTERISTICS</b>						
Analog Signal Range, $V_{ANALOG}$		Full	0		$V_+$	V
ON-Resistance, $r_{ON}$	$V_+ = 1.65V$ , $I_{COM} = 100mA$ , $V_{NO}$ or $V_{NC} = 0V$ to $V_+$ (see Figure 5)	25		0.7	0.8	$\Omega$
		Full			0.85	$\Omega$
<b>DYNAMIC CHARACTERISTICS</b>						
Turn-ON Time, $t_{ON}$	$V_+ = 1.65V$ , $V_{NO}$ or $V_{NC} = 1.0V$ , $R_L = 50\Omega$ , $C_L = 35pF$ (see Figure 1)	25		70		ns
		Full		80		ns
Turn-OFF Time, $t_{OFF}$	$V_+ = 1.65V$ , $V_{NO}$ or $V_{NC} = 1.0V$ , $R_L = 50\Omega$ , $C_L = 35pF$ (see Figure 1)	25		54		ns
		Full		65		ns
Break-Before-Make Time Delay, $t_d$	$V_+ = 2.0V$ , $V_{NO}$ or $V_{NC} = 1.0V$ , $R_L = 50\Omega$ , $C_L = 35pF$ (see Figure 3)	Full		10		ns
Charge Injection, Q	$C_L = 1.0nF$ , $V_G = 0V$ , $R_G = 0\Omega$ (see Figure 2)	25		42		pC
NO or NC OFF Capacitance, $C_{OFF}$	$f = 1MHz$ , $V_{NO}$ or $V_{NC} = V_{COM} = 0V$ (see Figure 7)	25		70		pF
COM ON Capacitance, $C_{COM(ON)}$	$f = 1MHz$ , $V_{NO}$ or $V_{NC} = V_{COM} = 0V$ (see Figure 7)	25		186		pF
<b>DIGITAL INPUT CHARACTERISTICS</b>						
Input Voltage Low, $V_{INL}$		25			0.4	V
Input Voltage High, $V_{INH}$		25	1.0			V
Input Current, $I_{INH}$ , $I_{INL}$	$V_+ = 2.0V$ , $V_{IN} = 0V$ or $V_+$ (Note 9)	Full	-0.5		0.5	$\mu A$

NOTES:

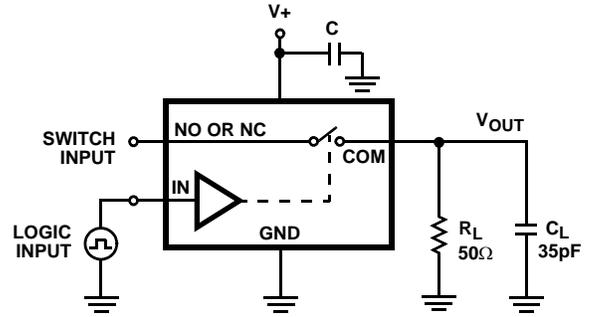
- $V_{IN}$  = input voltage to perform proper function.
- The algebraic convention, whereby the most negative value is a minimum and the most positive a maximum, is used in this data sheet.
- Flatness is defined as the difference between maximum and minimum value of on-resistance over the specified analog signal range.
- $r_{ON}$  matching between channels is calculated by subtracting the channel with the highest max  $r_{ON}$  value from the channel with lowest max  $r_{ON}$  value, between NC1 and NC2 or between NO1 and NO2.
- Parameters with MIN and/or MAX limits are 100% tested at  $+25^\circ C$ , unless otherwise specified. Temperature limits established by characterization and are not production tested.
- Limits established by characterization and are not production tested.

Test Circuits and Waveforms



Logic input waveform is inverted for switches that have the opposite logic sense.

FIGURE 1A. MEASUREMENT POINTS



Repeat test for all switches.  $C_L$  includes fixture and stray capacitance.

$$V_{OUT} = V_{(NO \text{ or } NC)} \frac{R_L}{R_L + r_{(ON)}}$$

FIGURE 1B. TEST CIRCUIT

FIGURE 1. SWITCHING TIMES

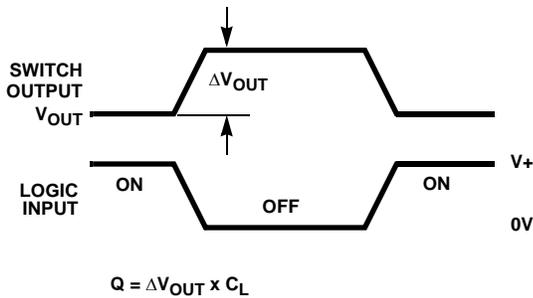
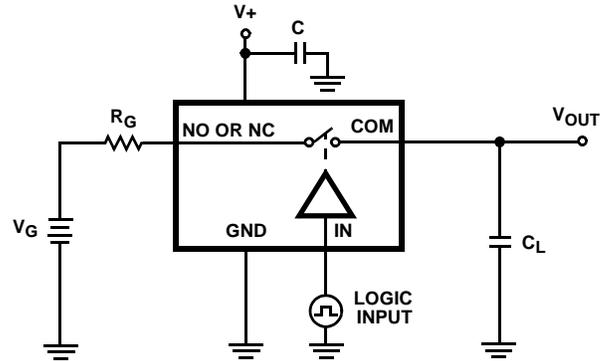


FIGURE 2A. MEASUREMENT POINTS



Repeat test for all switches.

FIGURE 2B. TEST CIRCUIT

FIGURE 2. CHARGE INJECTION

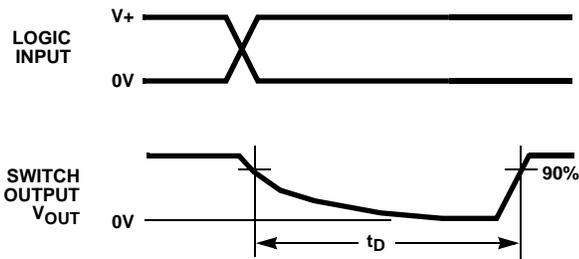
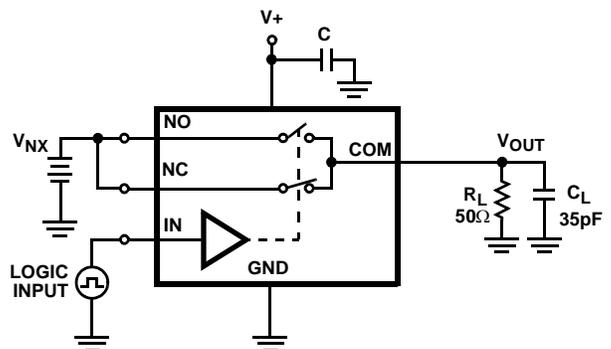


FIGURE 3A. MEASUREMENT POINTS

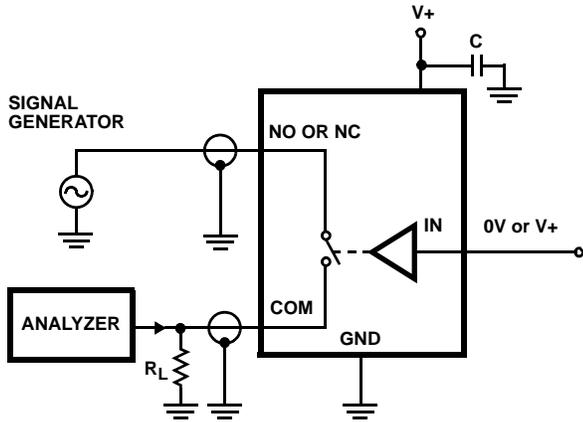


Repeat test for all switches.  $C_L$  includes fixture and stray capacitance.

FIGURE 3B. TEST CIRCUIT

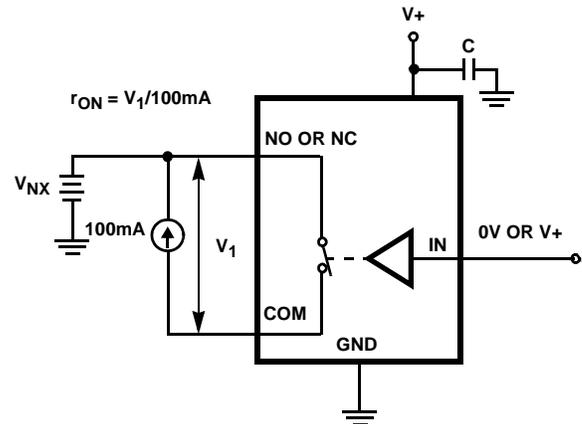
FIGURE 3. BREAK-BEFORE-MAKE TIME

## Test Circuits and Waveforms (Continued)



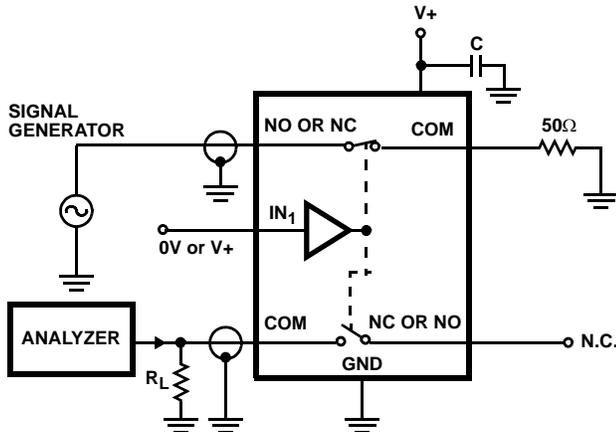
Signal direction through switch is reversed, worst case values are recorded. Repeat test for all switches.

FIGURE 4. OFF-ISOLATION TEST CIRCUIT



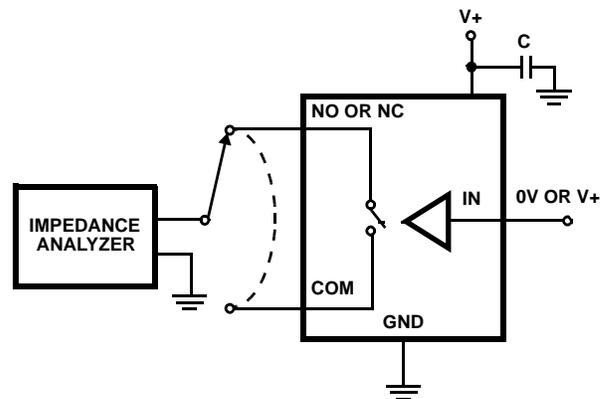
Repeat test for all switches.

FIGURE 5.  $r_{ON}$  TEST CIRCUIT



Signal direction through switch is reversed, worst case values are recorded. Repeat test for all switches.

FIGURE 6. CROSSTALK TEST CIRCUIT



Repeat test for all switches.

FIGURE 7. CAPACITANCE TEST CIRCUIT

## Detailed Description

The ISL54050 is a bidirectional, dual single pole/double throw (SPDT) analog switch that offers precise switching capability from a single 1.65V to 4.5V supply with low ON-resistance ( $0.29\Omega$ ) and high speed operation ( $t_{ON} = 40\text{ns}$ ,  $t_{OFF} = 20\text{ns}$ ). The device is especially well suited for portable battery powered equipment due to its low operating supply voltage (1.65V), low power consumption ( $4.5\mu\text{W}$  max), low leakage currents ( $195\text{nA}$  max), and the tiny  $\mu\text{TQFN}$  package. The ultra low ON-resistance and  $r_{ON}$  flatness provide very low insertion loss and distortion to applications that require signal reproduction.

### External V+ Series Resistor

For improved ESD and latch-up immunity, Intersil recommends adding a  $100\Omega$  resistor in series with the V+ power supply pin of the ISL54050 IC (see Figure 8).

During an overvoltage transient event, such as occurs during system level IEC 61000 ESD testing, substrate currents can be generated in the IC that can trigger parasitic SCR structures to turn ON, creating a low impedance path from the V+ power supply to ground. This will result in a significant amount of current flow in the IC, which can potentially create a latch-up state or permanently damage the IC. The external V+ resistor limits the current during this over-stress situation and has been found to prevent latch-up or destructive damage for many overvoltage transient events.

Under normal operation, the sub-microamp  $I_{DD}$  current of the IC produces an insignificant voltage drop across the  $100\Omega$  series resistor resulting in no impact to switch operation or performance.

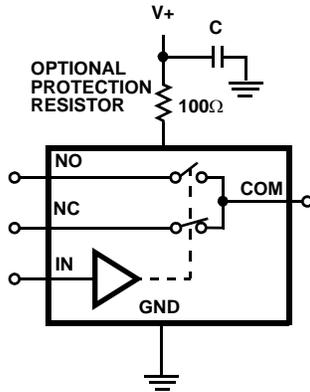


FIGURE 8. V+ SERIES RESISTOR FOR ENHANCED ESD AND LATCH-UP IMMUNITY

### Supply Sequencing and Overvoltage Protection

With any CMOS device, proper power supply sequencing is required to protect the device from excessive input currents, which might permanently damage the IC. All I/O pins contain ESD protection diodes from the pin to V+ and to GND (see Figure 9). To prevent forward biasing these diodes, V+ must be applied before any input signals, and the input signal voltages must remain between V+ and GND.

If these conditions cannot be guaranteed, then precautions must be implemented to prohibit the current and voltage at the logic pin and signal pins from exceeding the maximum ratings of the switch. The following two methods can be used to provide additional protection to limit the current in the event that the voltage at a signal pin or logic pin goes below ground or above the V+ rail.

Logic inputs can be protected by adding a 1kΩ resistor in series with the logic input (see Figure 9). The resistor limits the input current below the threshold that produces permanent damage, and the sub-micro amp input current produces an insignificant voltage drop during normal operation.

This method is not acceptable for the signal path inputs. Adding a series resistor to the switch input defeats the purpose of using a low  $r_{ON}$  switch. Connecting Schottky diodes to the signal pins, as shown in Figure 9, will shunt the fault current to the supply or to ground thereby protecting the switch. These Schottky diodes must be sized to handle the expected fault current.

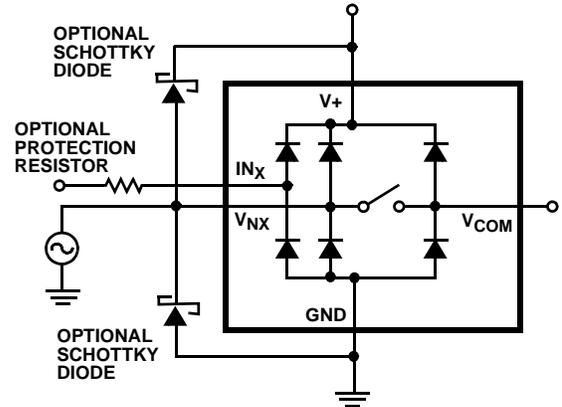


FIGURE 9. OVERVOLTAGE PROTECTION

### Power-Supply Considerations

The ISL54050 construction is typical of most single supply CMOS analog switches, in that they have two supply pins: V+ and GND. V+ and GND drive the internal CMOS switches and set their analog voltage limits. Unlike switches with a 4V maximum supply voltage, the ISL54050 5.5V maximum supply voltage provides plenty of room for the 10% tolerance of 4.3V supplies, as well as room for overshoot and noise spikes.

The minimum recommended supply voltage is 1.65V. It is important to note that the input signal range, switching times, and ON-resistance degrade at lower supply voltages. Refer to the “Electrical Specifications” tables starting on page 3 and “Typical Performance Curves” on page 9 for details.

V+ and GND also power the internal logic and level shifters. The level shifters convert the input logic levels to switched V+ and GND signals to drive the analog switch gate terminals.

This family of switches cannot be operated with bipolar supplies, because the input switching point becomes negative in this configuration.

### Logic-Level Thresholds

This switch family is 1.8V CMOS compatible (0.5V and 1.4V) over a supply range of 2.7V to 4.5V (see Figure 19). At 2.7V, the  $V_{IL}$  level is about 0.53V. This is still above the 1.8V CMOS guaranteed low output maximum level of 0.5V, but noise margin is reduced.

The digital input stages draw supply current whenever the digital input voltage is not at one of the supply rails. Driving the digital input signals from GND to V+ with a fast transition time minimizes power dissipation.

The ISL54050 has been designed to minimize the supply current whenever the digital input voltage is not driven to the supply rails (0V to V+). For example, driving the device with 2.85V logic (0V to 2.85V) while operating with a 4.2V supply, the device draws only 12μA of current (see Figure 17 for  $V_{IN} = 2.85V$ ).

**Frequency Performance**

In 50Ω systems, the ISL54050 has a -3dB bandwidth of 25MHz (see Figure 22). The frequency response is very consistent over a wide V+ range and for varying analog signal levels.

An OFF switch acts like a capacitor and passes higher frequencies with less attenuation, resulting in signal feed-through from a switch's input to its output. OFF-isolation is the resistance to this feed-through, while crosstalk indicates the amount of feed-through from one switch to another. Figure 23 details the high OFF-isolation and crosstalk rejection provided by this part. At 100kHz, OFF-isolation is about 62dB in 50Ω systems, decreasing approximately 20dB per decade as frequency increases. Higher load impedances decrease OFF-isolation and crosstalk rejection due to the voltage divider action of the switch OFF impedance and the load impedance.

**Leakage Considerations**

Reverse ESD protection diodes are internally connected between each analog signal pin and both V+ and GND. One of these diodes conducts if any analog signal exceeds V+ or GND.

Virtually all the analog leakage current comes from the ESD diodes to V+ or GND. Although the ESD diodes on a given signal pin are identical and therefore fairly well balanced, they are reverse biased differently. Each is biased by either V+ or GND and the analog signal. This means their leakages will vary as the signal varies. The difference in the two diode leakages to the V+ and GND pins constitutes the analog-signal-path leakage current. All analog leakage current flows between each pin and one of the supply terminals, not to the other switch terminal. This is why both sides of a given switch can show leakage currents of the same or opposite polarity. There is no connection between the analog signal paths and V+ or GND.

**Typical Performance Curves**  $T_A = +25^\circ\text{C}$ , Unless Otherwise Specified.

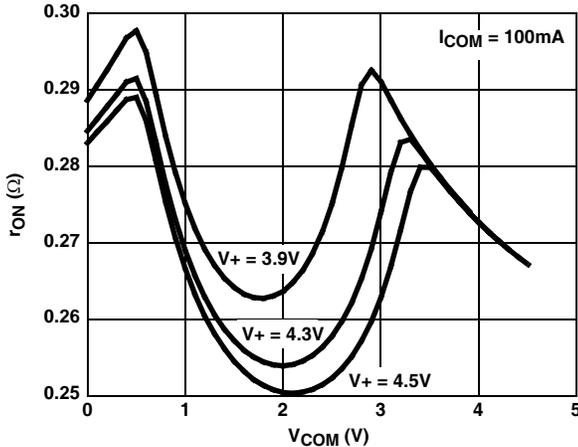


FIGURE 10. ON-RESISTANCE vs SUPPLY VOLTAGE vs SWITCH VOLTAGE

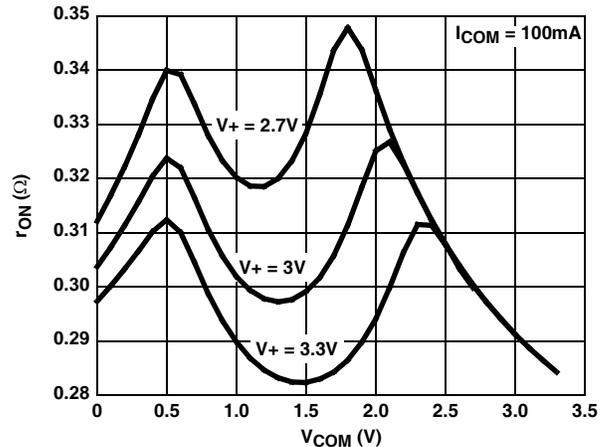


FIGURE 11. ON-RESISTANCE vs SUPPLY VOLTAGE vs SWITCH VOLTAGE

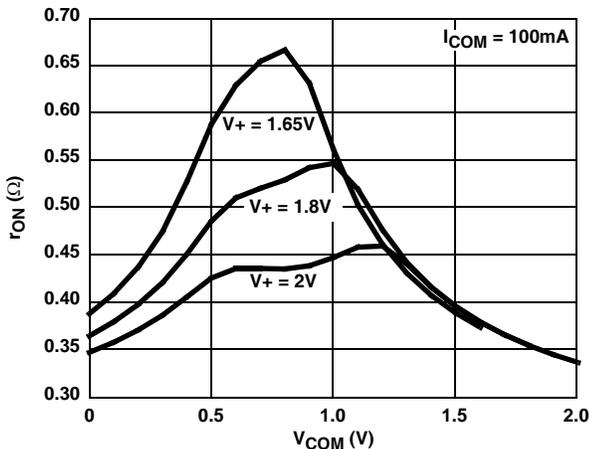


FIGURE 12. ON-RESISTANCE vs SUPPLY VOLTAGE vs SWITCH VOLTAGE

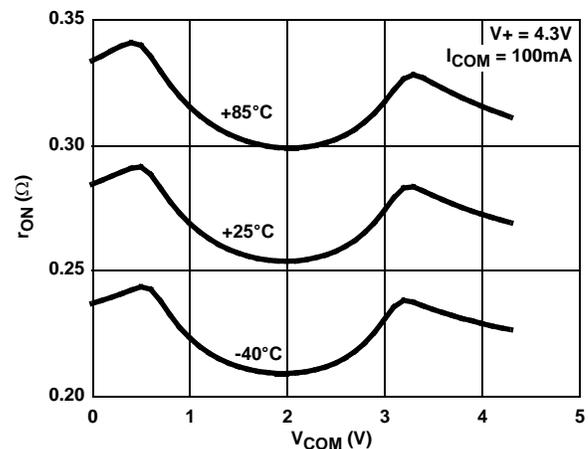


FIGURE 13. ON-RESISTANCE vs SWITCH VOLTAGE

**Typical Performance Curves**  $T_A = +25^\circ\text{C}$ , Unless Otherwise Specified. (Continued)

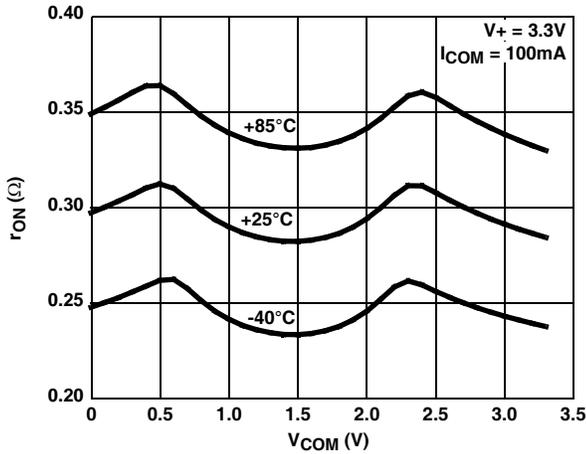


FIGURE 14. ON-RESISTANCE vs SWITCH VOLTAGE

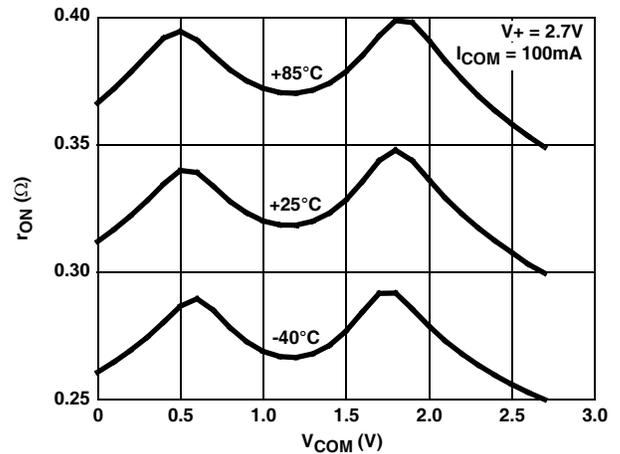


FIGURE 15. ON-RESISTANCE vs SWITCH VOLTAGE

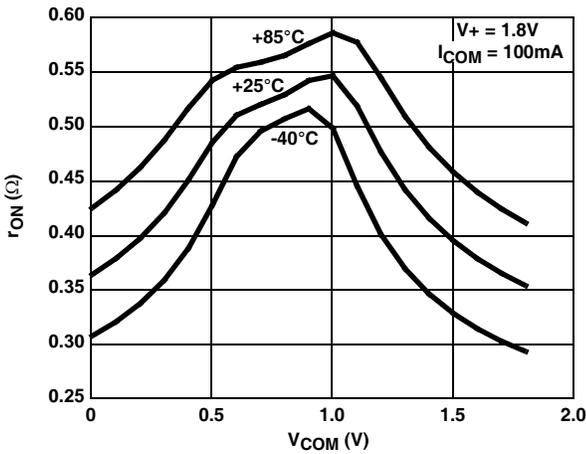


FIGURE 16. ON-RESISTANCE vs SWITCH VOLTAGE

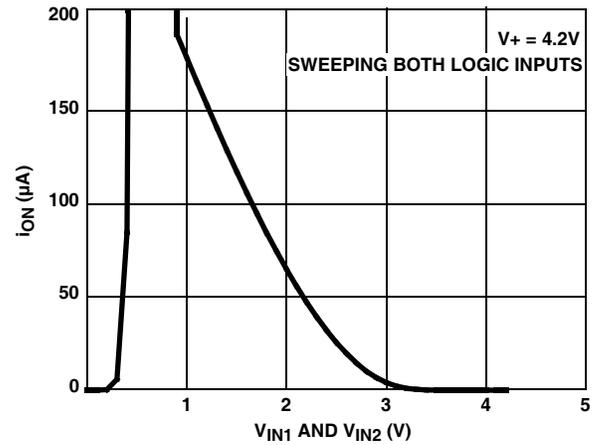


FIGURE 17. SUPPLY CURRENT vs VLOGIC VOLTAGE

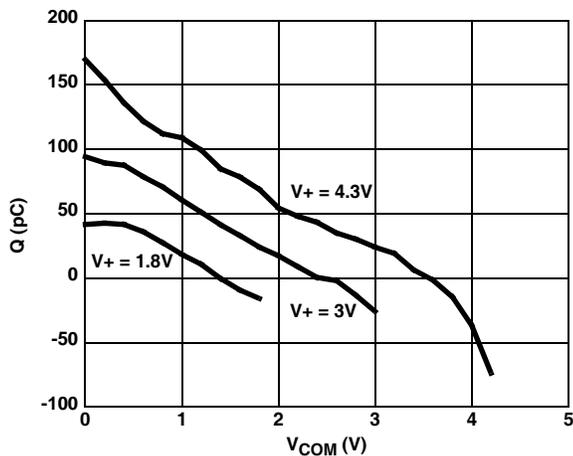


FIGURE 18. CHARGE INJECTION vs SWITCH VOLTAGE

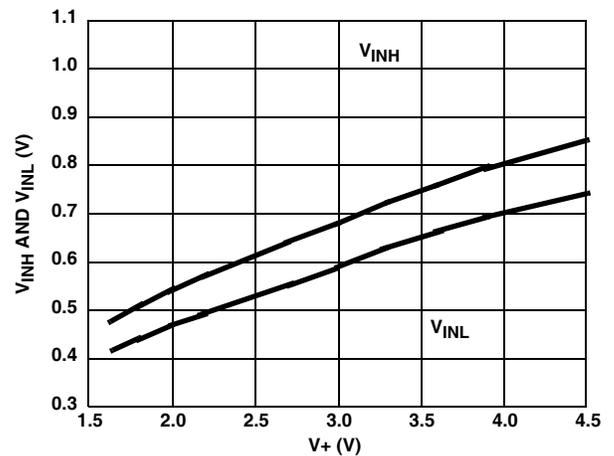


FIGURE 19. DIGITAL SWITCHING POINT vs SUPPLY VOLTAGE

**Typical Performance Curves**  $T_A = +25^\circ\text{C}$ , Unless Otherwise Specified. (Continued)

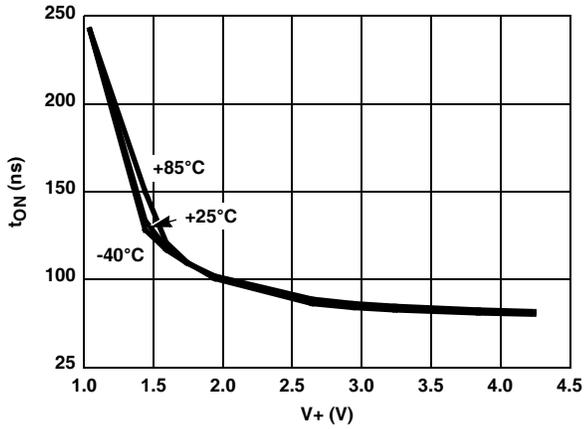


FIGURE 20. TURN-ON TIME vs SUPPLY VOLTAGE

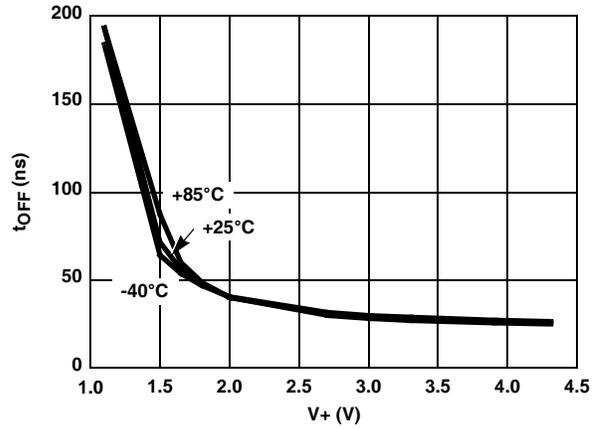


FIGURE 21. TURN-OFF TIME vs SUPPLY VOLTAGE

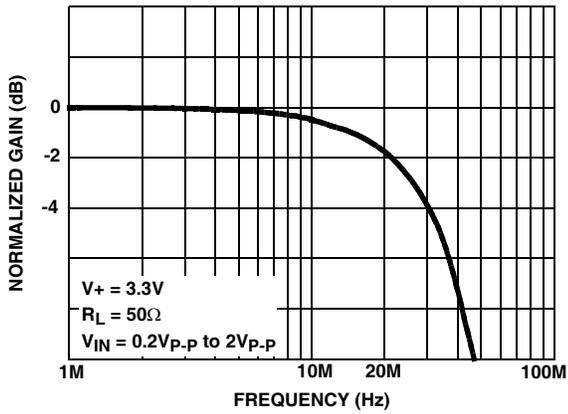


FIGURE 22. FREQUENCY RESPONSE

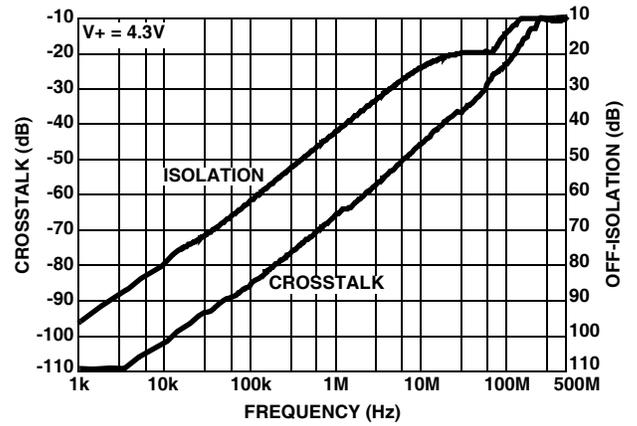
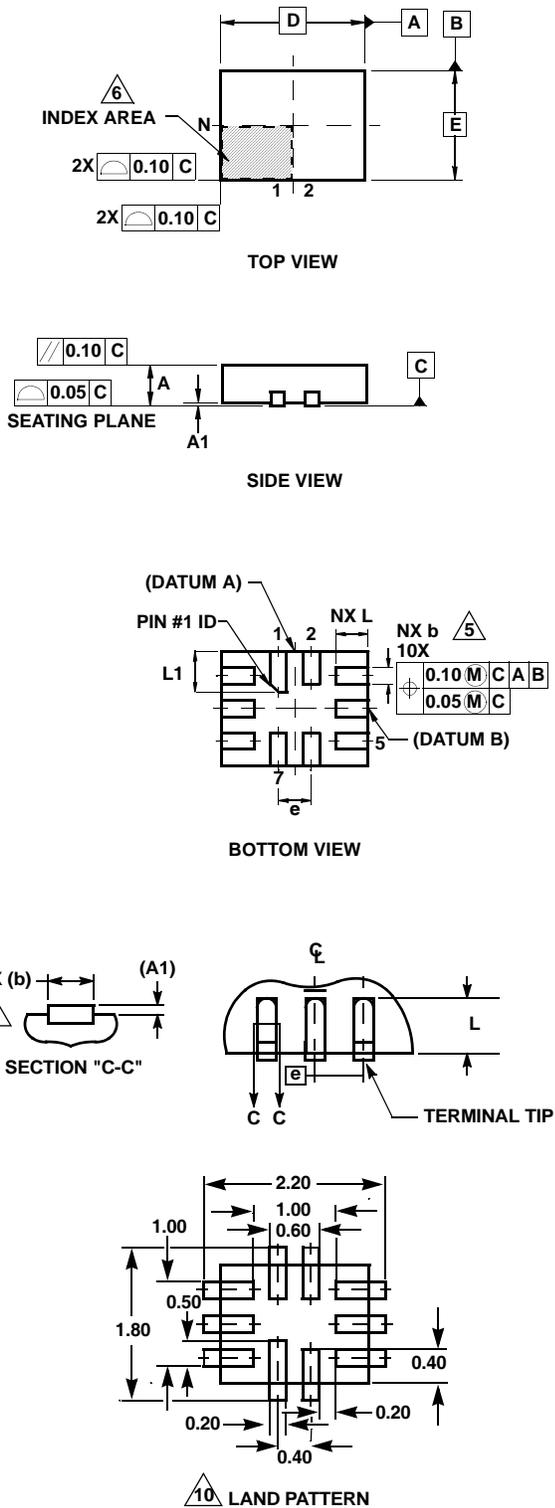


FIGURE 23. CROSSTALK AND OFF-ISOLATION

Ultra Thin Quad Flat No-Lead Plastic Package (UTQFN)



**L10.1.8x1.4A**  
10 LEAD ULTRA THIN QUAD FLAT NO-LEAD PLASTIC PACKAGE

SYMBOL	MILLIMETERS			NOTES
	MIN	NOMINAL	MAX	
A	0.45	0.50	0.55	-
A1	-	-	0.05	-
A3	0.127 REF			-
b	0.15	0.20	0.25	5
D	1.75	1.80	1.85	-
E	1.35	1.40	1.45	-
e	0.40 BSC			-
L	0.35	0.40	0.45	-
L1	0.45	0.50	0.55	-
N	10			2
Nd	2			3
Ne	3			3
θ	0	-	12	4

Rev. 3 6/06

NOTES:

1. Dimensioning and tolerancing conform to ASME Y14.5-1994.
2. N is the number of terminals.
3. Nd and Ne refer to the number of terminals on D and E side, respectively.
4. All dimensions are in millimeters. Angles are in degrees.
5. Dimension b applies to the metallized terminal and is measured between 0.15mm and 0.30mm from the terminal tip.
6. The configuration of the pin #1 identifier is optional, but must be located within the zone indicated. The pin #1 identifier may be either a mold or mark feature.
7. Maximum package warpage is 0.05mm.
8. Maximum allowable burrs is 0.076mm in all directions.
9. JEDEC Reference MO-255.
10. For additional information, to assist with the PCB Land Pattern Design effort, see Intersil Technical Brief TB389.

All Intersil U.S. products are manufactured, assembled and tested utilizing ISO9000 quality systems. Intersil Corporation's quality certifications can be viewed at [www.intersil.com/design/quality](http://www.intersil.com/design/quality)

Intersil products are sold by description only. Intersil Corporation reserves the right to make changes in circuit design, software and/or specifications at any time without notice. Accordingly, the reader is cautioned to verify that data sheets are current before placing orders. Information furnished by Intersil is believed to be accurate and reliable. However, no responsibility is assumed by Intersil or its subsidiaries for its use; nor for any infringements of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of Intersil or its subsidiaries.

For information regarding Intersil Corporation and its products, see [www.intersil.com](http://www.intersil.com)